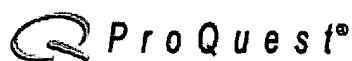


Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	7	"043712".ap.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/18 17:44
L2	174	(failure adj prediction).ab.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/18 17:46
L3	1	L2 and rve	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/18 17:44
L4	50	(failure near2 component same predict\$4).ab.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/18 17:46
L5	25	L4 and @ad<"20011025"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/18 17:49
L6	0	L5 and volume adj element	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/18 17:47
L7	2	rve same component same fail\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/18 17:54
L8	0	703/2.ccls. and (microstructure same component same fail\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/18 17:55
L9	0	703/6.ccls. and (microstructure same component same fail\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/18 17:55
L10	0	703/7.ccls. and (microstructure same component same fail\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/18 17:55

L11	0	703/?..cls. and (microstructure same component same fail\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/18 17:56
L12	40	(microstructure same component same fail\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/18 17:56
L13	0	702/?..cls. and (microstructure same component same fail\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/18 17:57
L14	0	702/34..cls. and (microstructure same component same fail\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/18 17:56
L15	3	(micro-structure same component same fail\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/18 17:56
L16	0	702/?..cls. and (\$6structure same component same fail\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/18 17:57
L17	12	703/?..cls. and (\$6structure same component same fail\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/18 17:57

[Return to the USPTO NPL Page](#) | [Help](#)

Interface language:

English

[What's new](#)

Databases selected: Multiple databases...

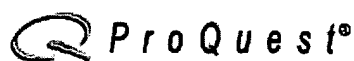
Searching for *(RVE and component failure) AND PDN(<10/25/2001)* did not find any documents. Try the following:

Suggested Topics [About](#)< Previous | [Next >](#)**Browse Suggested Publications**
[About](#)< Previous |
Next >[Business failures](#)[Business failures AND Failure](#)[Business failures AND Success](#)[Business failures AND Small business](#)[Harvard Business Review; Boston](#)[Dun and Bradstreet, Inc. D & B Reports; New York](#)[Journal of Small Business Management; Milwaukee](#)**-OR-****Revise** your search below using the following tips:

- Check your spelling.
- Reduce the number of terms included in your search.
- Broaden your search by selecting other [databases](#), removing limits, or searching "Citations and Document Text" (if available).
- Use "AND" to connect two words that don't need to be searched as a phrase.
- Connect similar terms with the "OR" operator (e.g. military OR pentagon). See [Search Tips](#) for more hints.

Basic Search

Tools: [Search Tips](#) [Browse Topics](#) [1 Recent Searches](#)Database: Date range: [About](#)Limit results to: ☐ Full text documents only ☐ Scholarly journals, including peer-reviewed [About](#)[More Search Options](#)Copyright © 2005 ProQuest Information and Learning Company. All rights reserved. [Terms and Conditions](#)[Text-only interface](#)

[Return to the USPTO NPL Page](#) | [Help](#)**Basic**

Advanced

Topics

Publications

My Research

0 marked items

Interface language:

English

[What's new](#)

Databases selected: Multiple databases...

Results – powered by ProQuest® Smart Search**Suggested Topics** [About](#)< Previous | [Next](#) >[Economic theory](#)[Economic theory AND Securities trading](#)[Economic theory AND Securities markets](#)[Economic theory AND Mathematical models](#)**Browse Suggested Publications**< Previous | [Next](#) >[About](#)[Automotive Industries; Radnor](#)[Journal of Financial and Quantitative Analysis; Seattle](#)[Metallurgical and Materials Transactions; Warrendale](#)1 document found for: *(microstructure and component failure) AND PDN(<10/25/2001)* [Set up Alert](#) [About](#)

Dissertations

☐ Mark all 0 marked items: Email / Cite / Export

Show only full text

Sort results by: [Most rec](#)

- ☐ 1. **MOSFET technology for ultra-large-scale integration**
by Yu, Bin, Ph.D., University of California, Berkeley, 1997, 147 pages; AAT 9827169

Abstract

24 Page Preview

Page Image - PDF

Order a c

1-1 of 1

Want an alert for new results sent by email? [Set up Alert](#) [About](#)

Results per

Basic SearchTools: [Search Tips](#) [Browse Topics](#) [2 Recent Searches](#)

microstructure and component failure

[Search](#)[Clear](#)Database: [Multiple databases...](#) [Select multiple databases](#)Date range: [Before this date...](#) [10/25/2001](#) [About](#)Limit results to: ☐ Full text documents only ☐ Scholarly journals, including peer-reviewed [About](#)[More Search Options](#)Copyright © 2005 ProQuest Information and Learning Company. All rights reserved. [Terms and Conditions](#)[Text-only interface](#)**ProQuest**
COMPANY